

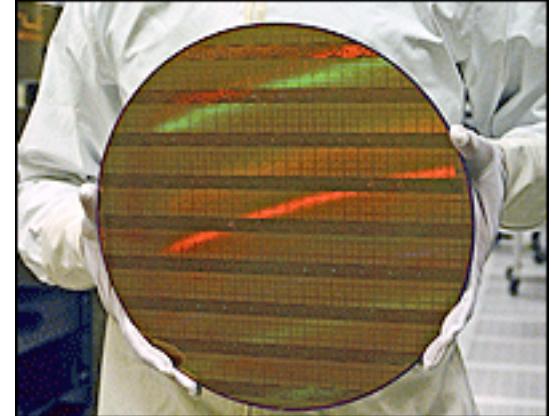
# Mesoscopic Electronics

ChiiDong Chen, Institute of Physics, Academia Sinica  
中央研究院 物理研究所 陳啟東

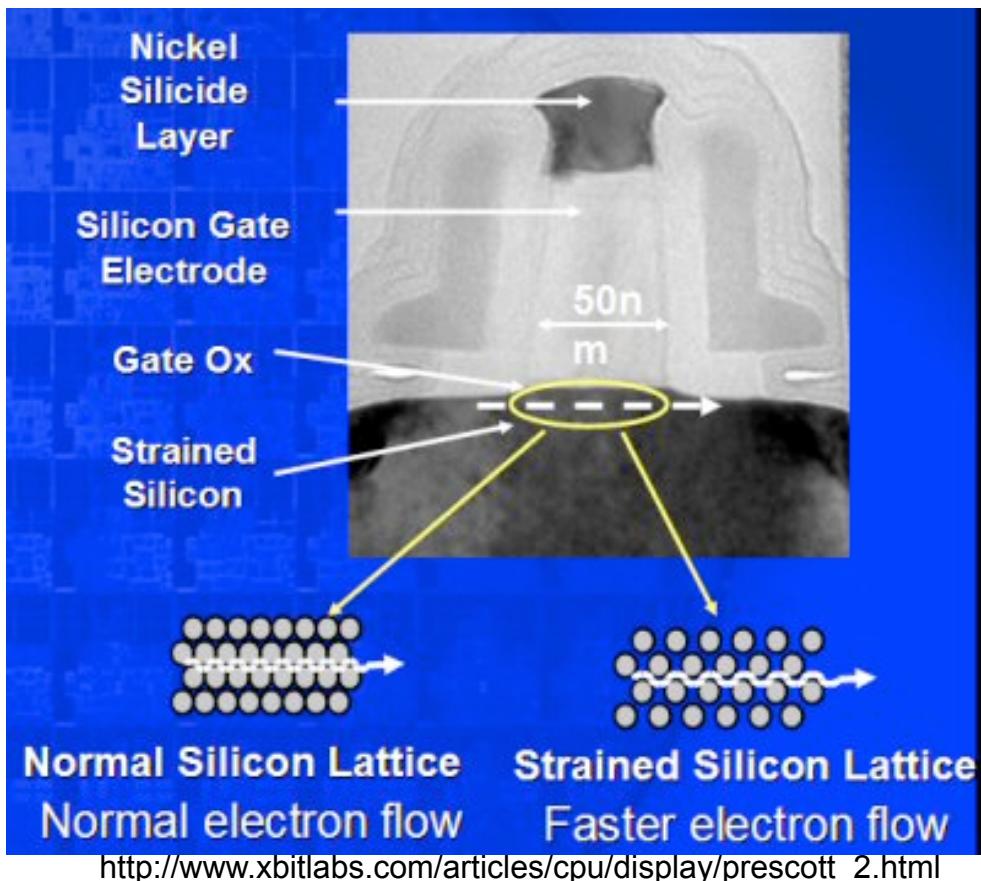
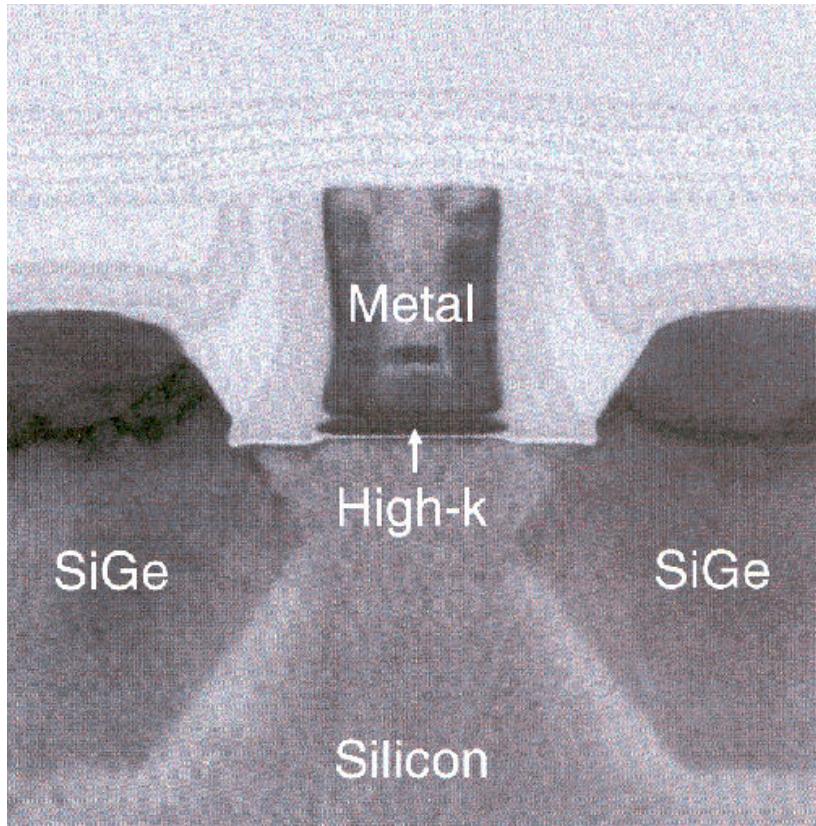
chiidong@phys.sinica.edu.tw.  
<http://www.phys.sinica.edu.tw/~quela/>

Cheng-Kung University, Tainan, Taiwan  
Tokyo Institute of Technology, Tokyo, Japan  
Chalmers University, Gothenburg, Sweden

# Present-day semiconductor industry

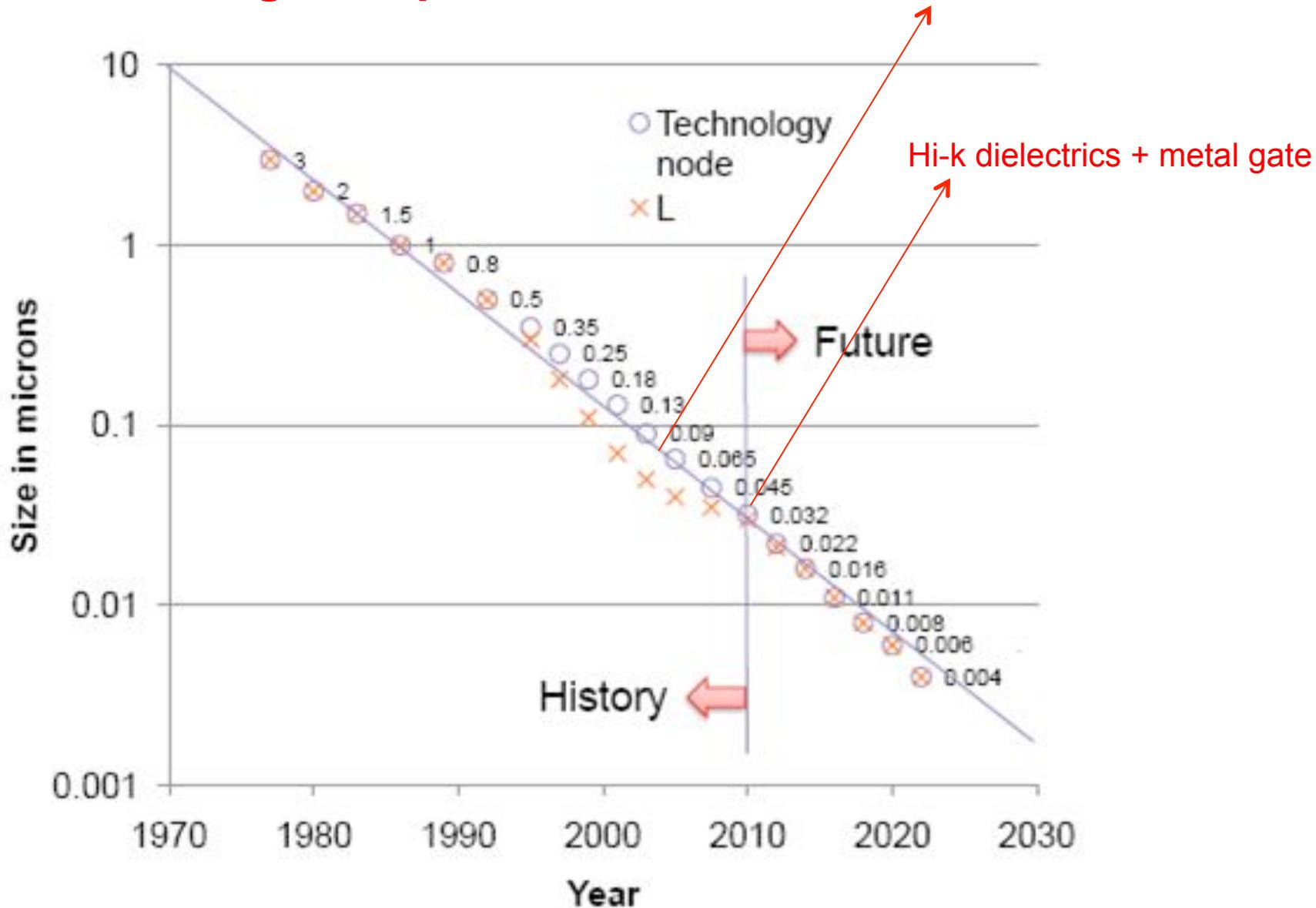


Scientific American, January 30, 2007



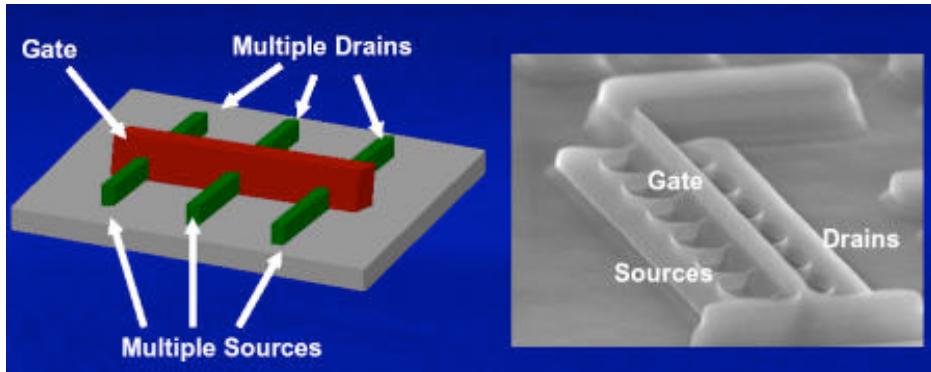
# Gate length map

## Strained Silicon

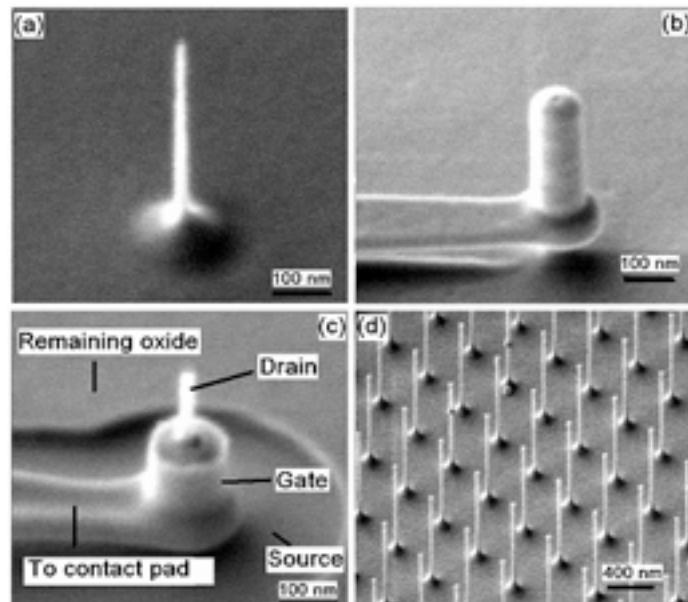


# Latest development and future technologies

## FinFET or Multi-gate FET (MuGFET)

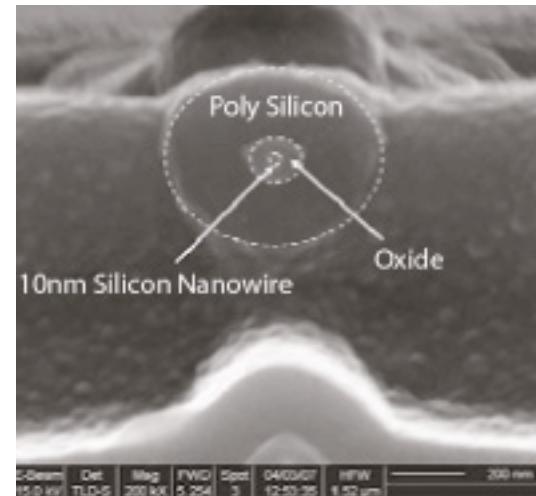
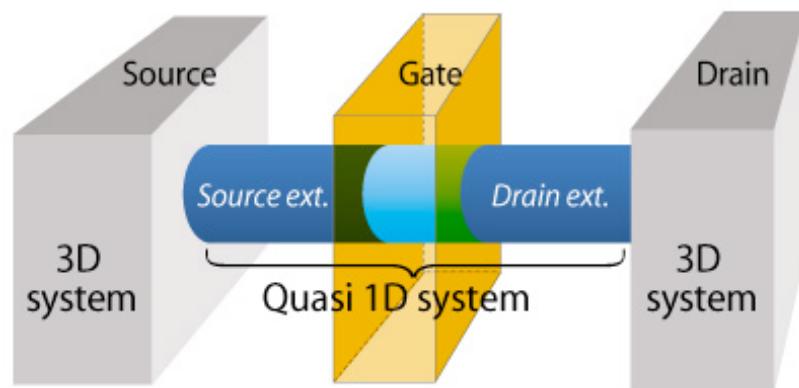


## Vertical Silicon-Nanowire Formation



<http://www.ime.a-star.edu.sg/html/newsrelease/2008/Shortcuts-May08Jun08.htm>

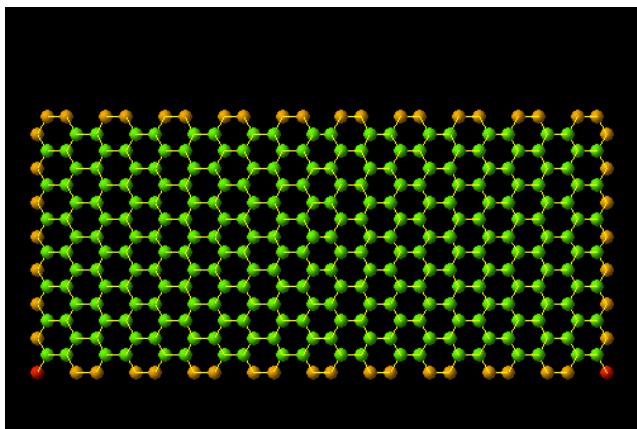
## Gate-All-Around Field-Effect-Transistors



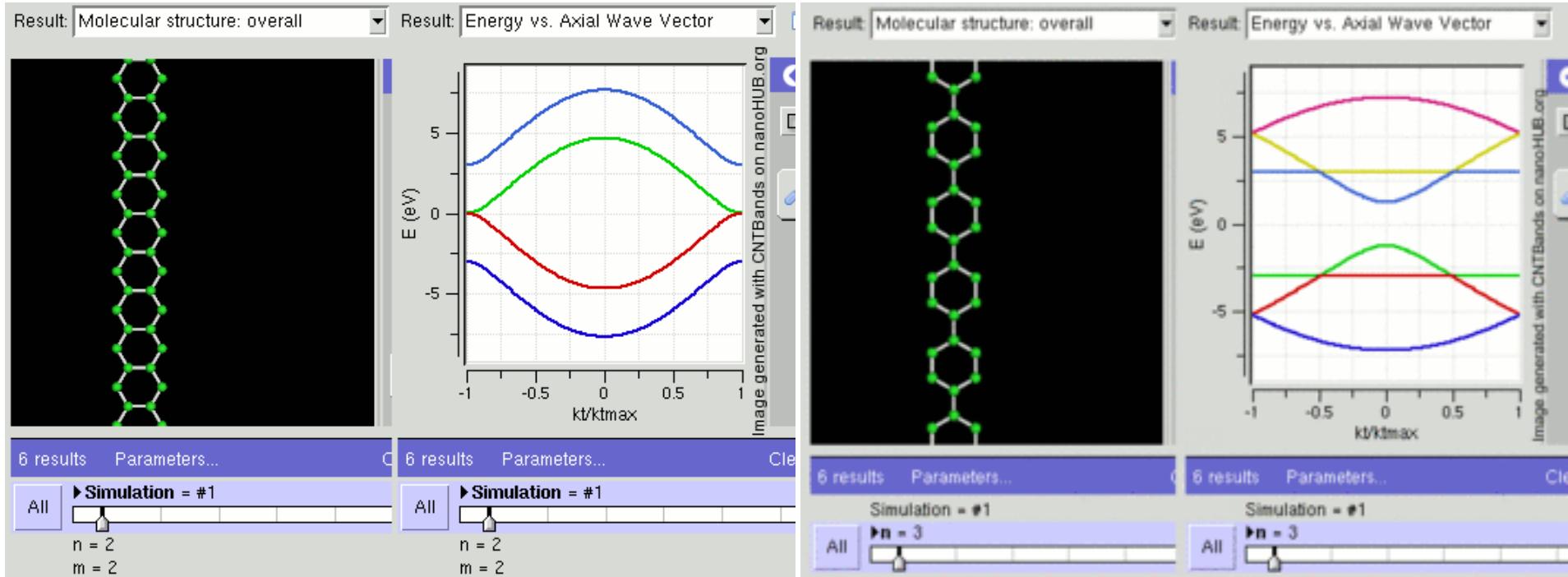
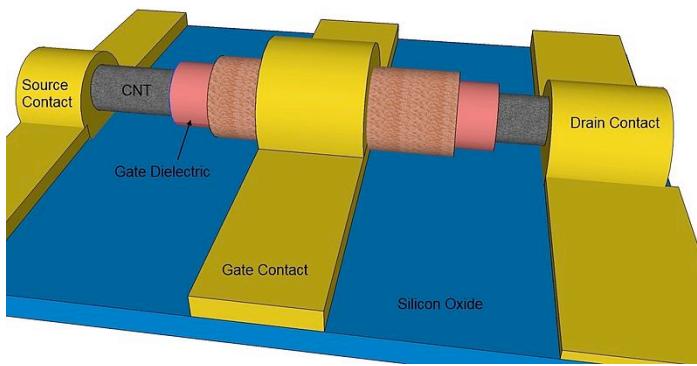
<http://www.advancedsubstratenews.com/2010/12/Advanced-Substrate-Corners>

Posted by [Professor Ru HUANG](#) on December 8, 2010

# Carbon nanotube and Graphene Electronics



Gate-All-Around CNT



Do we see “quantum effect”  
in the present-day semiconductor devices?

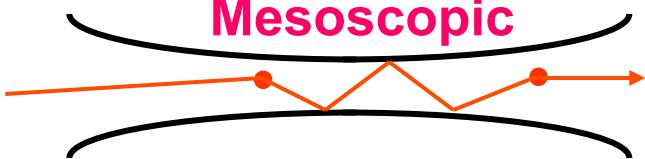
# Characteristic length scales

Ballistic



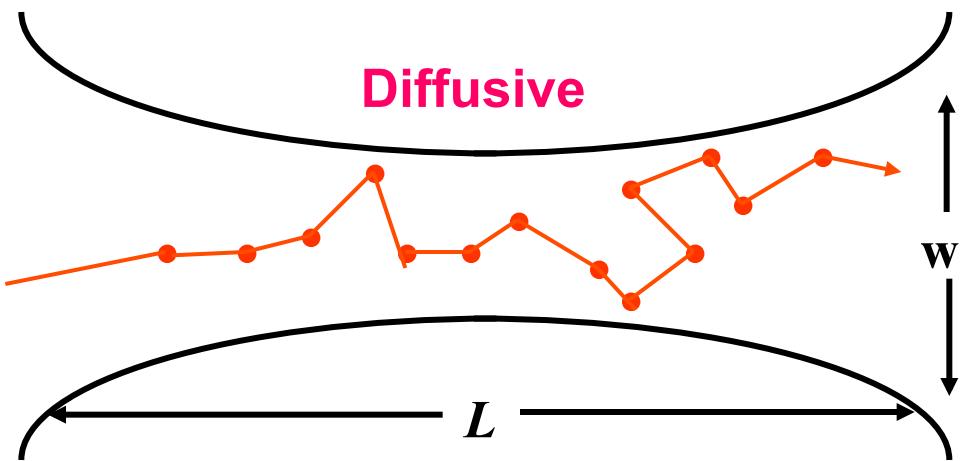
$$(w, L) < l$$

Mesoscopic

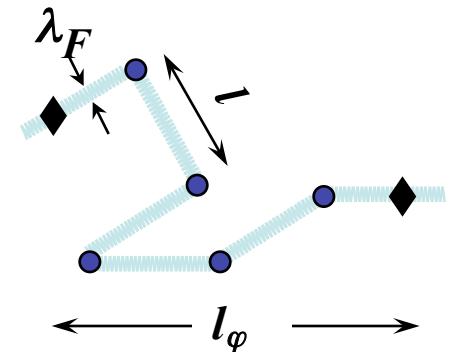


$$l < (w, L) < L_\varphi$$

Diffusive



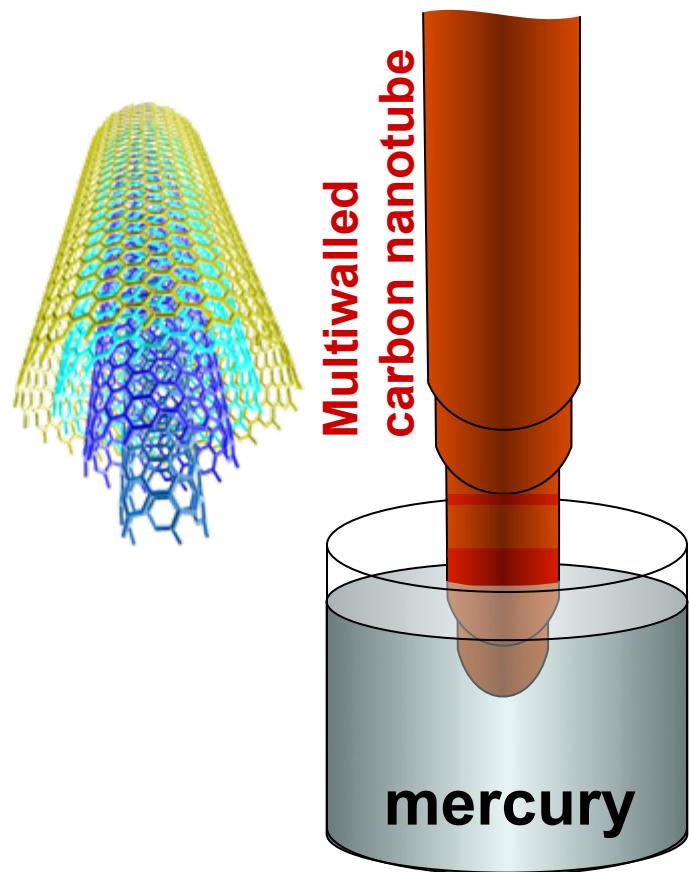
$$L_\varphi \ll (w, L)$$



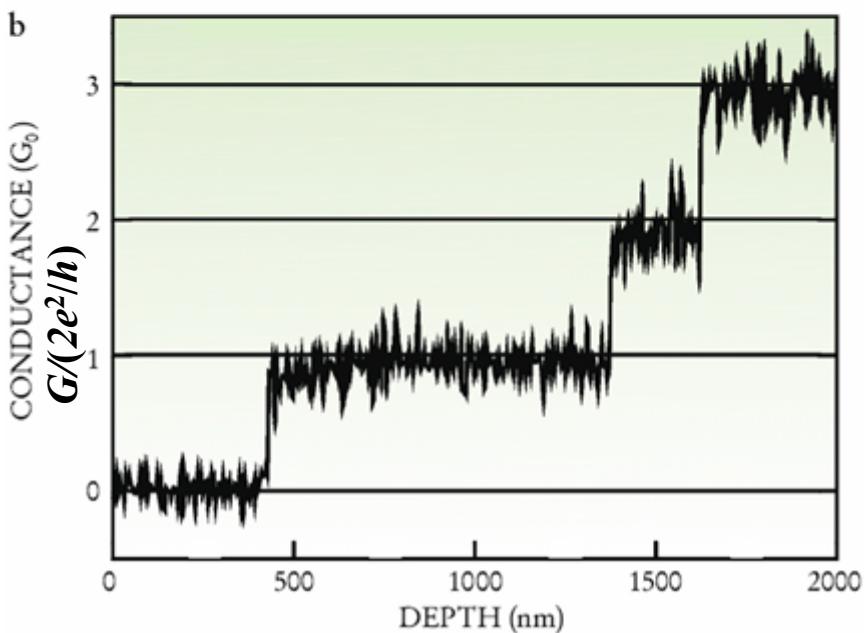
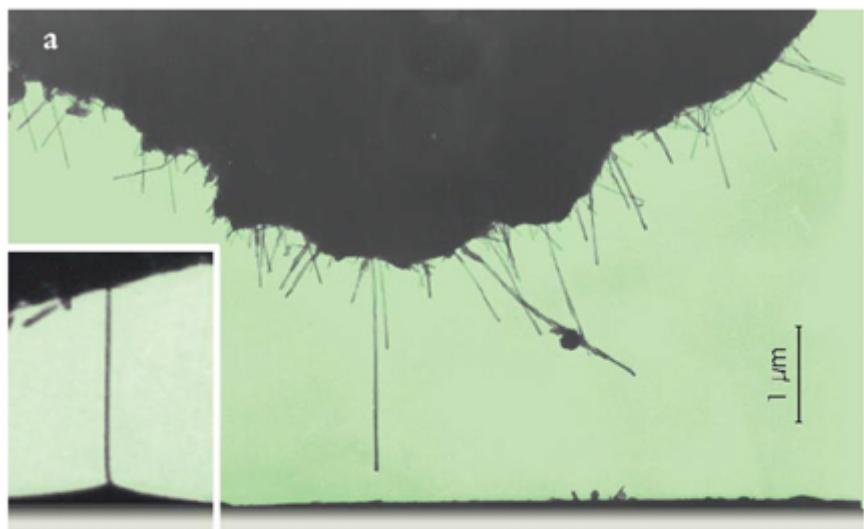
$l$  : elastic mean free path

$L_\varphi$  : phase-breaking length

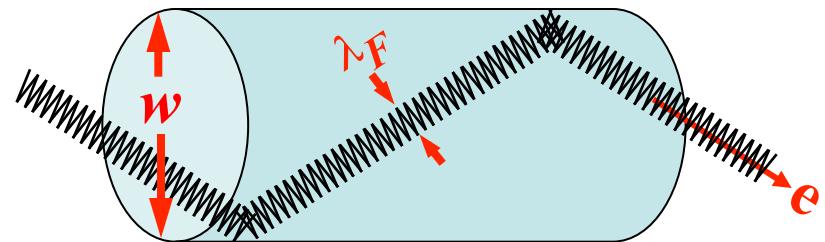
# Ballistic transport: Length independent conductance



Walt de Heer,  
Georgia Institute of Technology



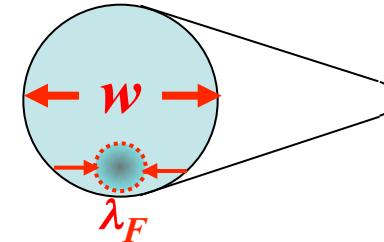
# Ballistic system:



Devices with

1. Small diameter → only a few conduction channels

$$N \approx \pi w^2 / \pi \lambda_F^2$$



2. weak  $e$ - $e$  interaction
3. No impurity, no defect → no impurity scattering

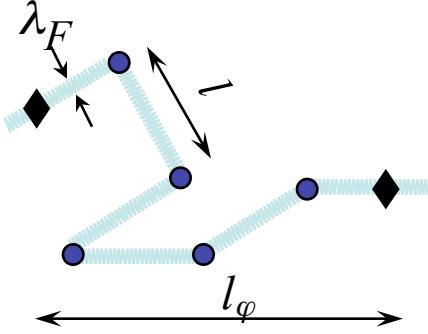
$$G_0 = N 2e^2/h$$

$$R_0 = \frac{1}{N} \frac{h}{2e^2} = \frac{R_Q}{N} \approx \frac{6.5k\Omega}{N}$$

$R_Q$ : quantum resistance

Resistance independent of the length,  
only determined by number of channels  $N$

Resistance takes place at the macroscopic contacts



inelastic mean free path  
(phase breaking length)

$$l_\varphi = \sqrt{D\tau_\varphi}$$

$l_\varphi \approx 0.1 \sim 1 \text{ } \mu\text{m}$  for metal

$l_\varphi \approx 0.2 \sim 20 \text{ } \mu\text{m}$  for GaAs

elastic mean free path  $l = v_F \tau$

$l \approx 0.01 \sim 0.1 \text{ } \mu\text{m}$  for metal

$l \approx 0.1 \sim 10 \text{ } \mu\text{m}$  for GaAs

Fermi wavelength  $\lambda_F = 2\pi/k_F$

$\lambda_F \approx 0.4 \text{ nm}$  for metal

$\lambda_F \approx 40 \text{ nm}$  for GaAs

large

Ohm's law, drift eq., Einstein relation, Drude model

"usual" devices

Mesoscopic regime: to include quantum interference corrections

Weak localization, Aharonov-Bohm oscillation, Universal conductance fluctuations, persistent currents, ... in small metallic wires, rings, Si MOSFETs, ..

Quantum ballistic transportation:  
the conductance fully determined by quantum mechanics

Conductance quantization, Quantum Hall effects in Quantum point contact, GaAs-based heterostructures

Quantum size effects:  
Quantum confinement

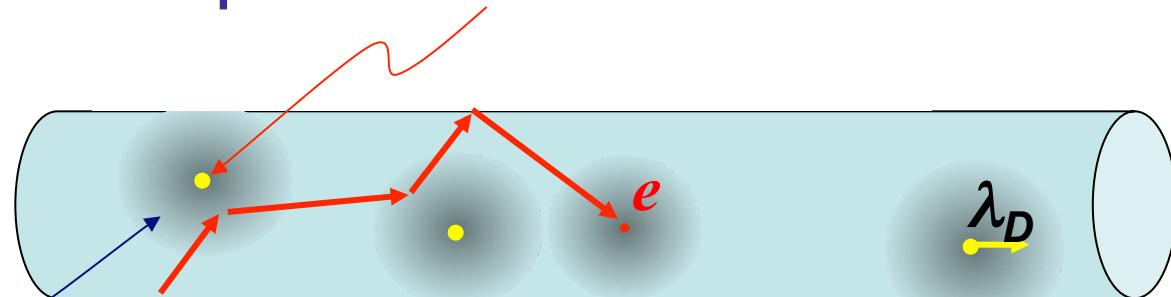
Energy level splitting in small metallic particles, GaAs-base quantum dots

small

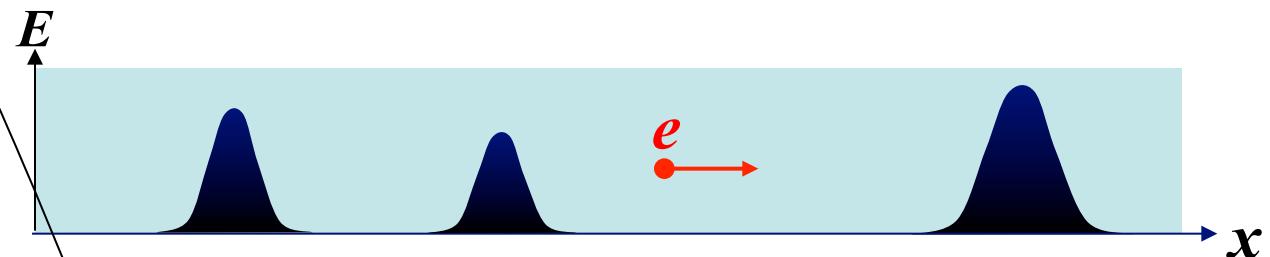
# Origin of resistance

electron transport in disorder systems

impurities / defects / dislocation /other carriers



impurity potential

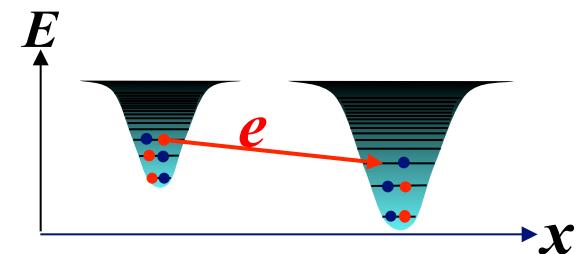
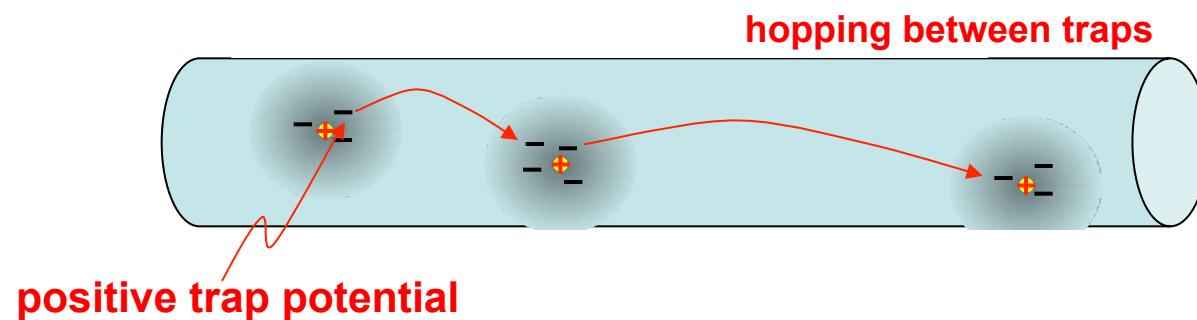
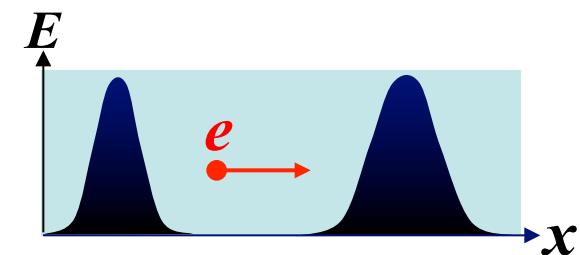
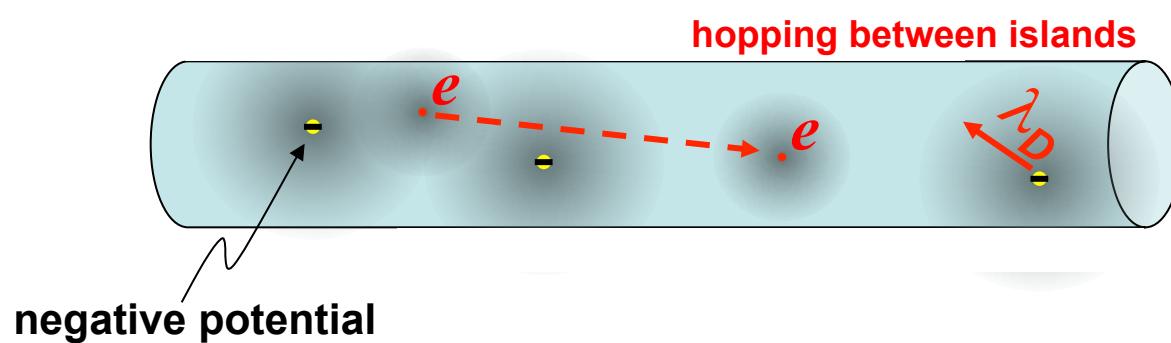


$$i\hbar \frac{\partial \Psi}{\partial t} = \left( -\frac{\hbar^2}{2m} \frac{\partial^2}{\partial x^2} + V \right) \Psi$$

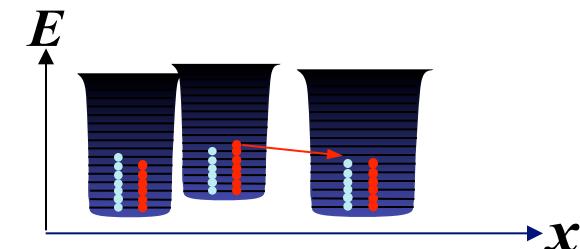
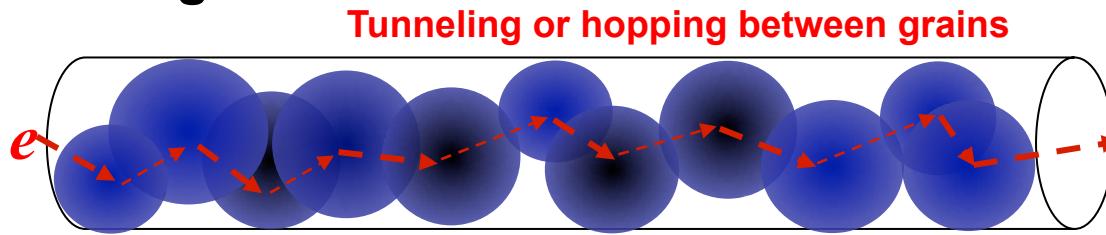
$$\text{Debye length } \lambda_D = \sqrt{\epsilon k_B T / e^2 N_i}$$

$\epsilon$  = dielectric permittivity,  
 $k_B$  = Boltzmann constant,  
 $T$  = absolute temperature,  
 $e$  = electron charge

# Hopping conduction in disordered systems

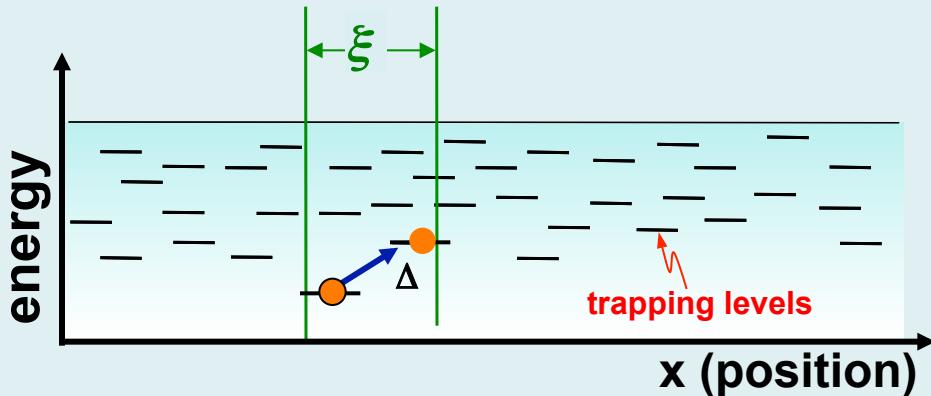


## Metallic grains



# Hopping transport $R_0$ increases with decreasing temperature

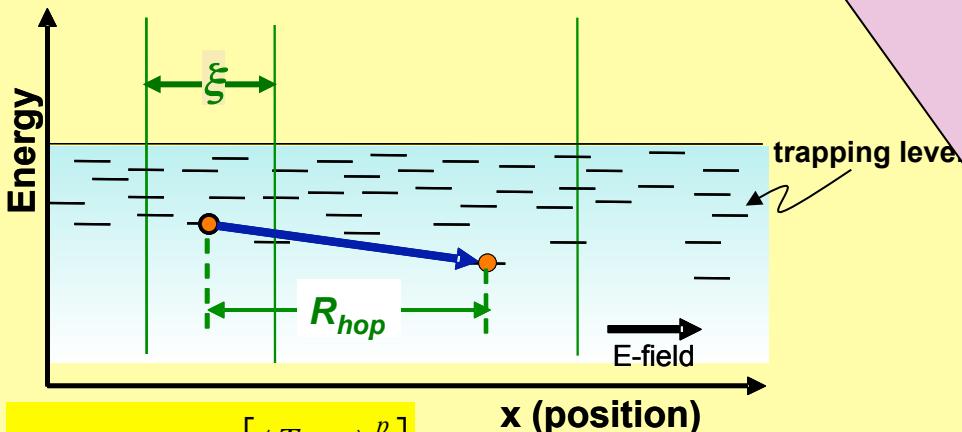
## Nearest neighbor hopping (Arrhenius form)



$$R_0 = R_A \exp\left(-\frac{\Delta}{k_B T}\right)$$

Presence of a **hopping barrier**; thermally activated hopping

## Mott Variable range hopping



$$R_0 = R_A T^S \exp\left[-\left(\frac{T_{Mott}}{T}\right)^p\right]$$

$T_{Mott}$  = Mott characteristic temperature

$$p = \frac{1}{1+d} d = \text{system dimensionality}$$

## Efros-Shklovskii Variable range hopping

when Coulomb interaction is considered

$$R_0 = R_A T^S \exp\left[-\left(\frac{T_{ES}}{T}\right)^{1/2}\right]$$

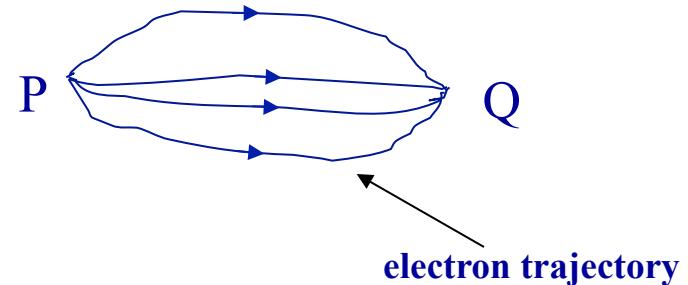
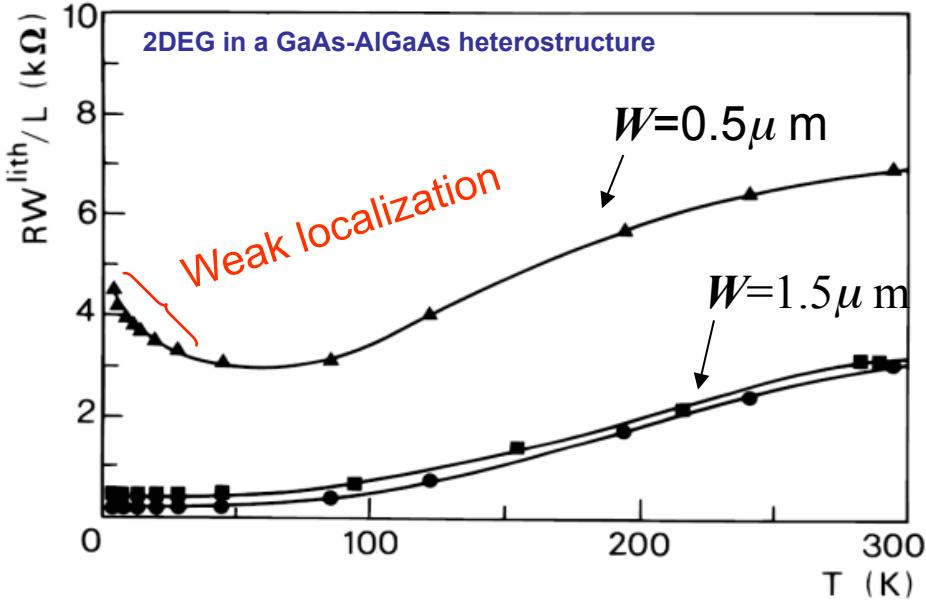
power-law dependence in DOS near  $E_F$

$$N(E) = N_0 |E - E_F|^\gamma$$

For 3D,  $\gamma=2$

Nonlinear IV<sub>b</sub> characteristics

# Weak localization takes place for length scale $< L_\phi$



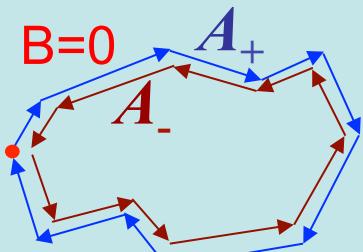
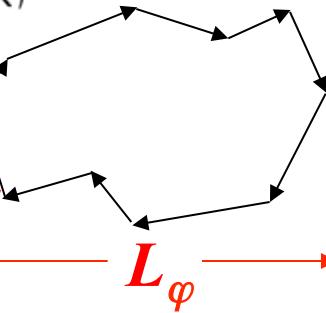
Probability for  $P \rightarrow Q$

$$W_{P \rightarrow Q} = \left| \sum_i A_i \right|^2 = \underbrace{\sum_i |A_i|^2}_{\text{Classical diffusion}} + \underbrace{\sum_{i \neq j} A_i A_j^*}_{\text{Quantum interference}}$$

"backscattering" event : ( $P=Q$ )

time reversal symmetry

elastic scattering



In zero field,  $B=0$ ,  $A_+ = A_- = A$

Probability for back-scattering

$$W_{P \leftrightarrow P} = |A_+ + A_-|^2 = 4|A|^2$$

# Suppression of weak localization by a magnetic field

In a field  $\mathbf{B} = \nabla \times \mathbf{A}$

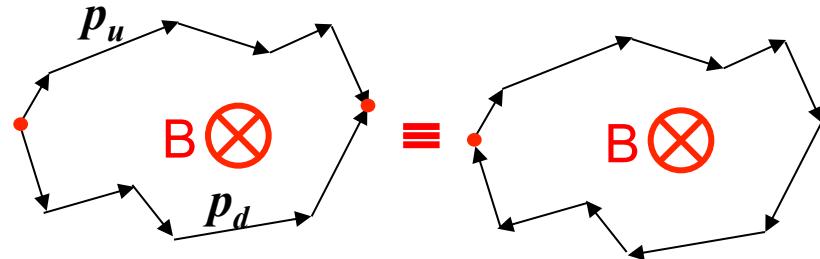
Canonical momentum

$$p = mv - eA$$

electrons pick a phase  $\varphi$   
when traveling along a path  $P$

$$\varphi = \frac{e}{\hbar} \int_P \mathbf{A} \cdot d\mathbf{x}$$

Magnetic field: **break** the time reversal symmetry

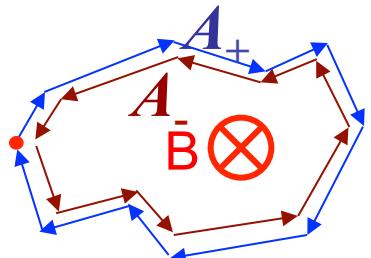


phase difference between two paths with the same ends

$$\begin{aligned} \delta\phi &= \frac{1}{\hbar} \int_P^Q p_u \cdot dl_1 - \frac{1}{\hbar} \int_P^Q p_d \cdot dl_2 = \boxed{\frac{e}{\hbar} \int_P^Q \mathbf{A}_u \cdot d\mathbf{l}_1 + \frac{e}{\hbar} \int_Q^P \mathbf{A}_d \cdot d\mathbf{l}_2} = \frac{e}{\hbar} \oint \mathbf{A} \cdot d\mathbf{l} \\ &= \frac{e}{\hbar} \int (\nabla \times \mathbf{A}) \cdot dS = \frac{e}{\hbar} \int B dS = 2\pi \frac{B \cdot S}{h/e} = \text{acquired phase around a loop} \end{aligned}$$

phase difference between  $A_+$  and  $A_-$  =

$$2\delta\phi = 2\pi \frac{B \cdot S}{h/2e}$$

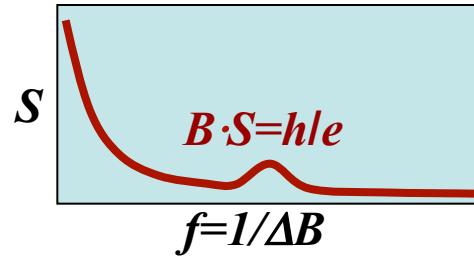
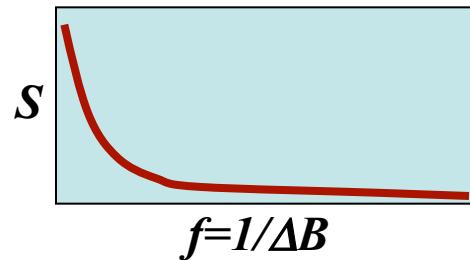
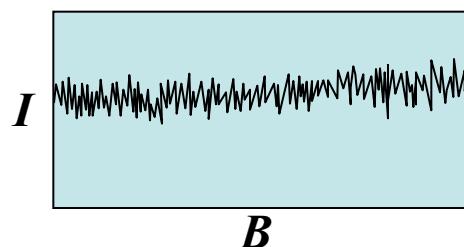
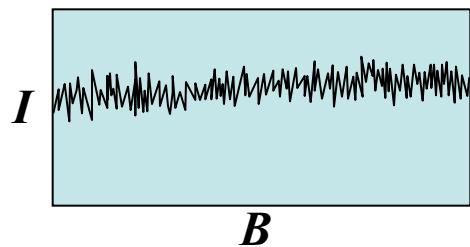
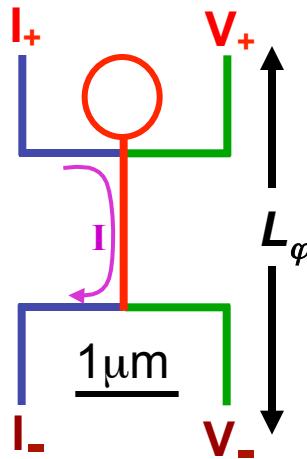
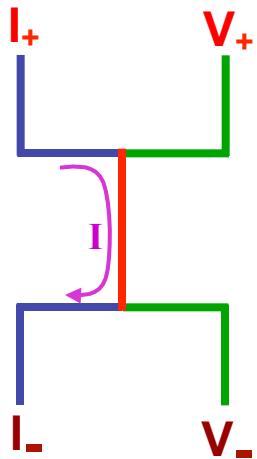


Probability for back-scattering

$$W_{P \leftrightarrow P} = 2|A|^2 + 2|A|^2 \cos\left(2\pi \frac{B \cdot A}{h/2e}\right)$$

$$< 4|A|^2$$

# Quantum correction to the conduction



The quantum correction to the conductance can be strongly influenced by phase coherent regions extending beyond the probes and outside the classical current paths

## Observation of $h/e$ Aharonov-Bohm Oscillations in Normal-Metal Rings

R. A. Webb, S. Washburn, C. P. Umbach, and R. B. Laibowitz  
*IBM Thomas J. Watson Research Center, Yorktown Heights, New York 10598*  
 (Received 27 March 1985)

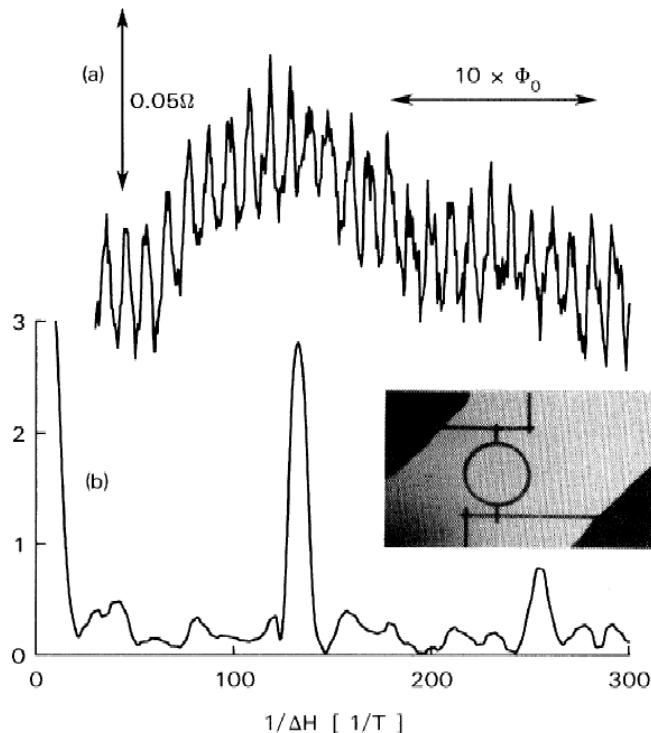


FIG. 1. (a) Magnetoresistance of the ring measured at  $T = 0.01$  K. (b) Fourier power spectrum in arbitrary units containing peaks at  $h/e$  and  $h/2e$ . The inset is a photograph of the larger ring. The inside diameter of the loop is 784 nm, and the width of the wires is 41 nm.

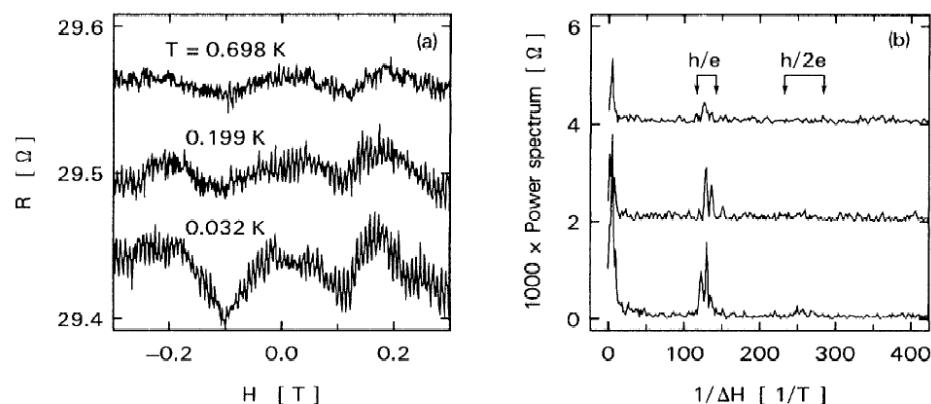
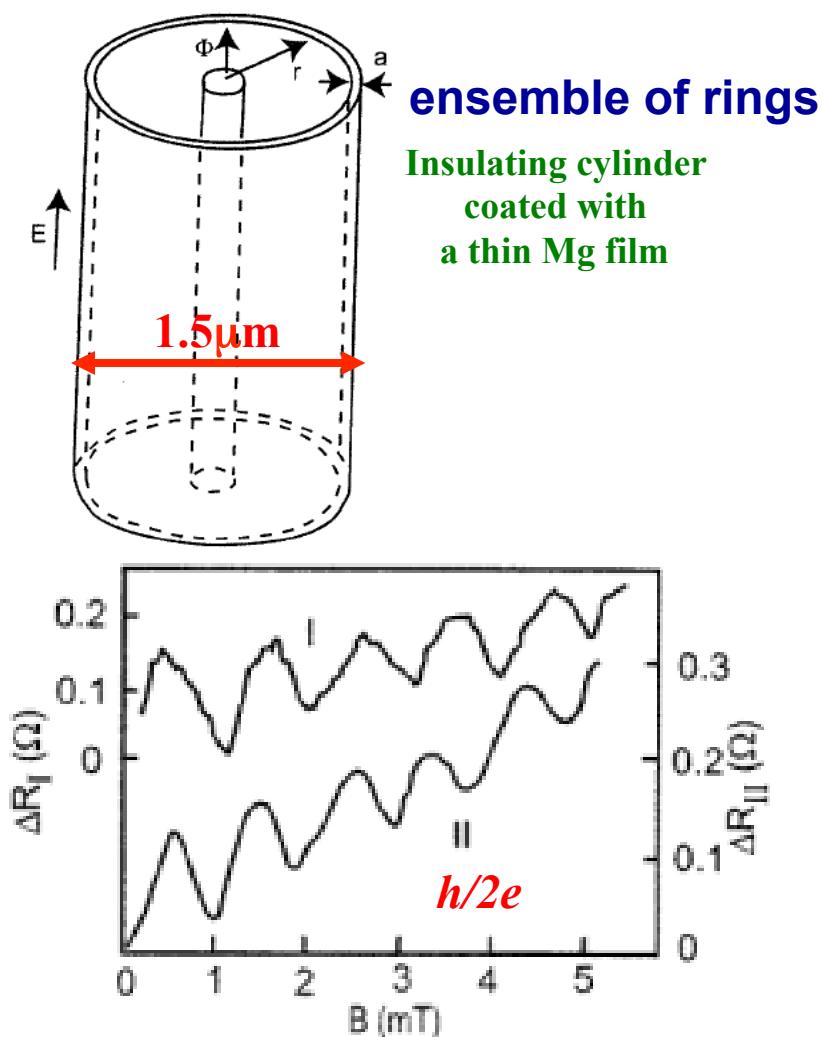
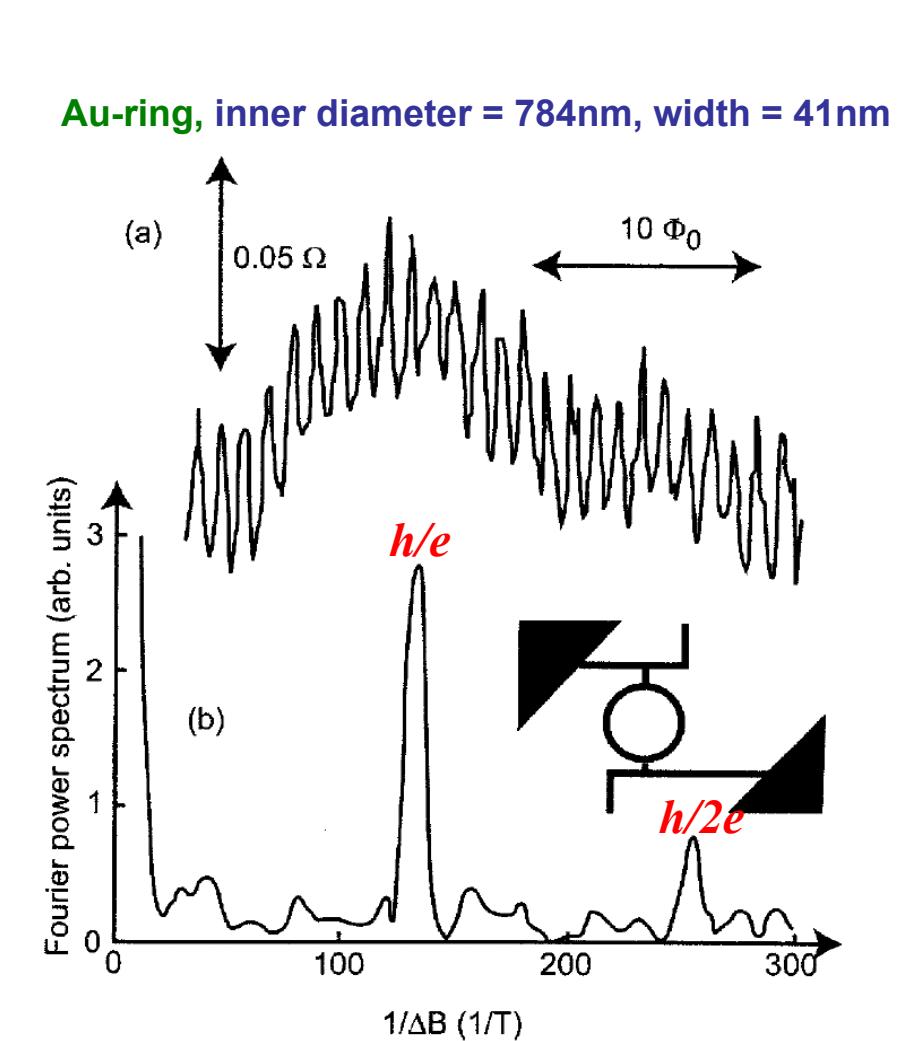


FIG. 2. (a) Magnetoresistance data from the ring in Fig. 1 at several temperatures. (b) The Fourier transform of the data in (a). The data at  $0.199$  and  $0.698$  K have been offset for clarity of display. The markers at the top of the figure indicate the bounds for the flux periods  $h/e$  and  $h/2e$  based on the measured inside and outside diameters of the loop.

# Experimental evidences :



Sharvin and Sharvin. JEPT Lett, 34, 272 (1981)  
***h/e is averaged out***

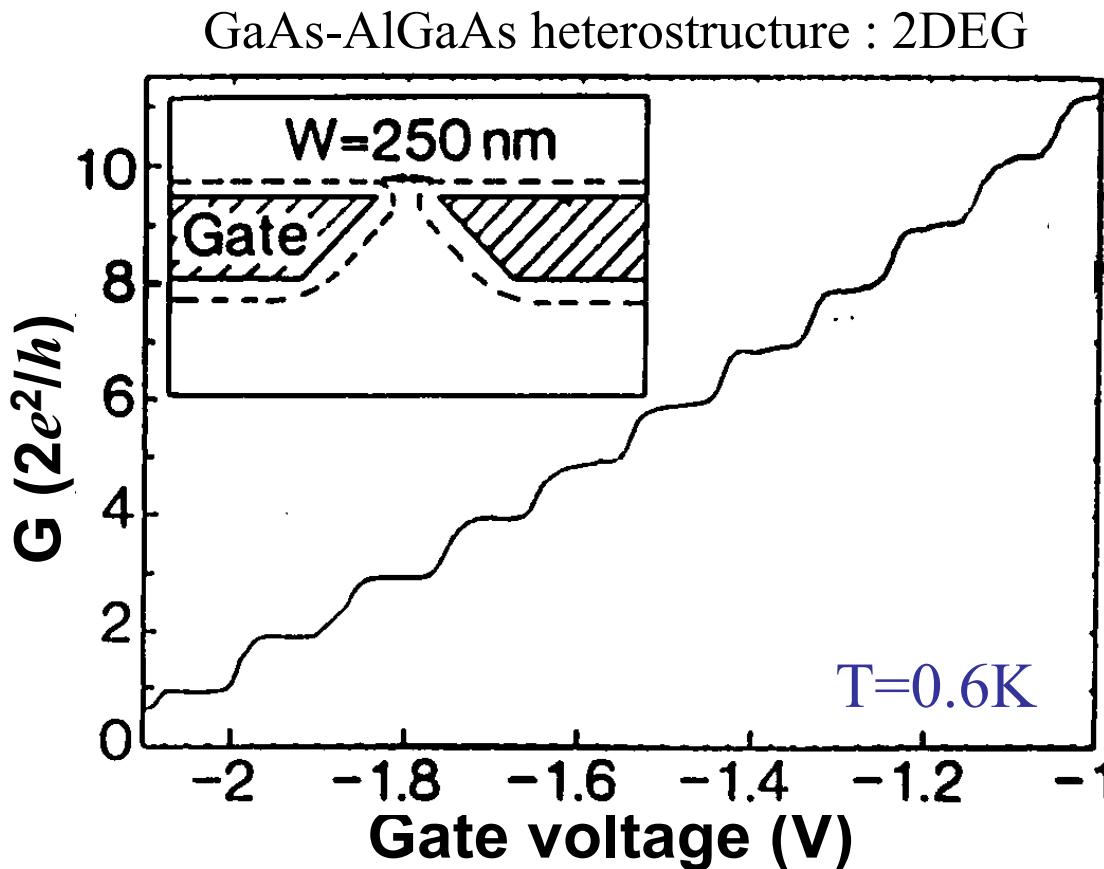


R.A. Webb et al. PRL, 54, 2696 (1985)

# Conductance Quantization

## Experiments on Quantum Point Contacts

B.J.van Wees et al. PRL 60, 848 (1988)



$$G = \frac{2e^2}{h} \sum_n^N T_n(E_F)$$

$$T_n(E_F) = \sum_{n=1}^N |t_{m \rightarrow n}|^2$$

For adiabatic constriction

$$t_{m \rightarrow n} = \delta_{nm}$$

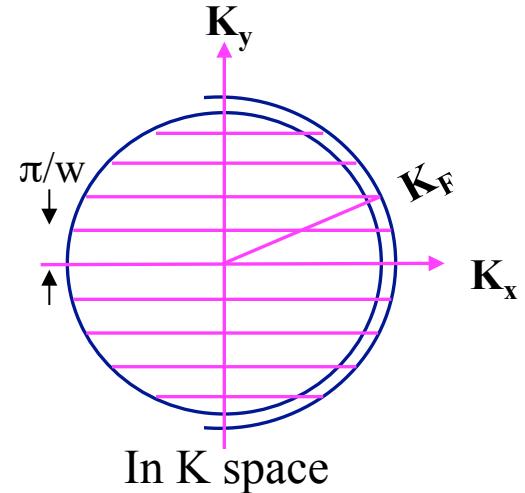
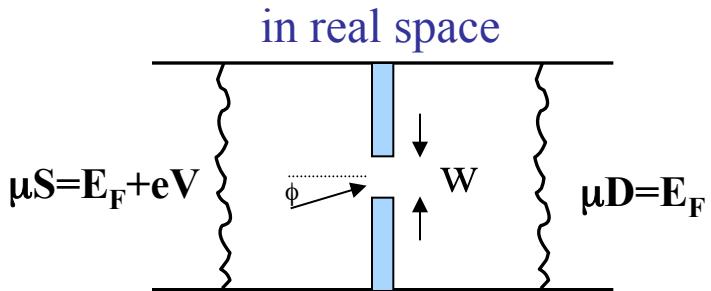
For abrupt constriction

$$t_{m \rightarrow n} \neq 1$$

Optimized gate length

$$L_{opt} \approx 0.4\sqrt{\omega \lambda_F}$$

# The origin of the conductance quantization



**Diffusion current**

$$I = e \sum_n^N \int_{E_F}^{E_F + eV} dE \rho_n(E) v_n(E) T_n(E)$$

**1D Density of state**

$$= \frac{1}{\pi} \left( \frac{dE_n}{dk} \right)^{-1} \frac{1}{\cos \phi}$$

**transmission probability**

$$= \frac{2e}{h} eV \sum_n^N T_n(E_F)$$

**Group velocity**

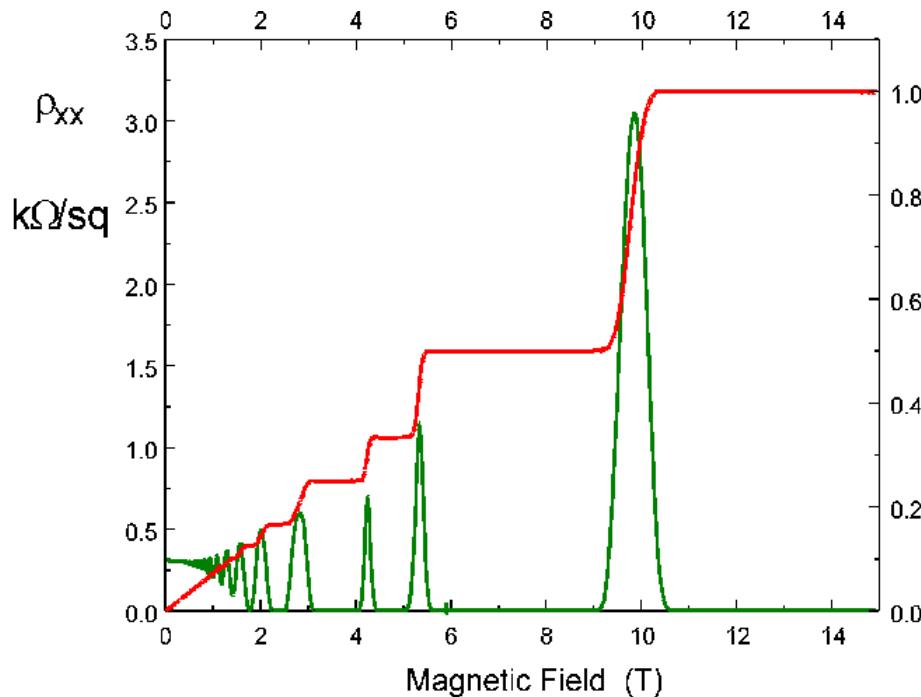
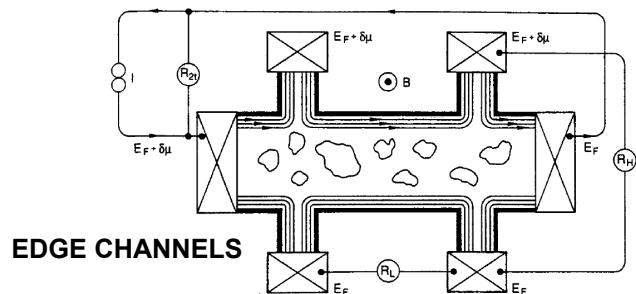
$$= \frac{1}{\hbar} \left( \frac{dE_n}{dk} \right) \cos \phi$$

$$N = \frac{w}{\lambda_F / 2}$$

**Landauer Formula for contact conductance**

$$G = \frac{2e^2}{h} \sum_n^N T_n(E_F) = \frac{2e^2}{h} \frac{W}{\lambda_F / 2}$$

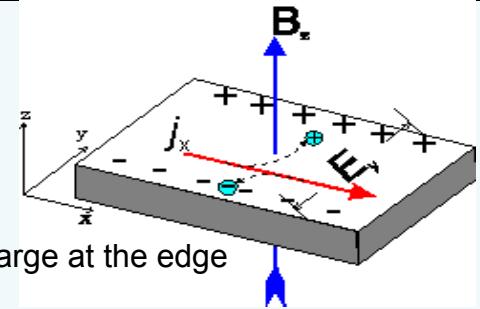
# Quantum Hall Effect



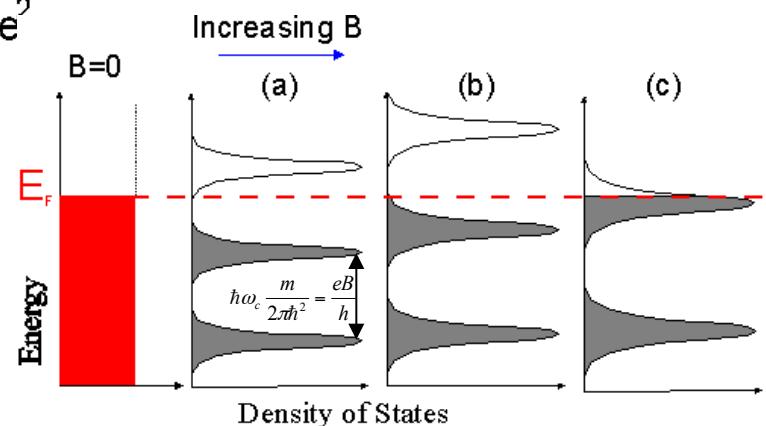
Hall effect:

magnetic force = electrostatic force  
from the build up of charge at the edge

$$R_H = E_y / j_x = 1/Nq$$



$$\frac{mv^2}{r} = evB, v = r\omega_c \Rightarrow m\omega_c = eB$$



The value of resistance only depends on the fundamental constants of physics.

Resistance standard since 1990:  $h/25812.806$  Ohms (precision )

<http://www.warwick.ac.uk/~phsbm/qhe.htm>

## Energy Scales

Green light (550nm) = 2.25eV

Band gap (Si :1.1 eV, GaAs : 1.4 eV) (TiO<sub>2</sub> : 3.0 eV)

Superconductor energy gap ( $2\Delta$ )

(Nb :3.0 meV, Pb : 2.7 meV, Al : 0.34 meV)

Coulomb interaction energy (charging energy)

( $e^2/C \approx 0.5$  meV ~ 10 meV) (6 K ~ 120 K)

Cyclotron energy for 2DEG at 1Tesla ( $\hbar eB/m^* \sim 1.7$  meV)

Level spacing

( $\hbar^2/m^* R^2 \approx 0.12$  meV for a 100 nm 2DEG disc)

( $2/N_0(\varepsilon_F)V \approx 0.15$  meV for a 5 nm spherical metal particle)

Thermal energy ( $k_B T$ ) 1 K ≈ 86 μeV

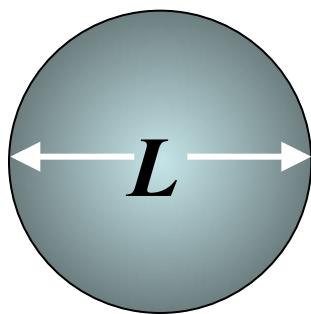
Spin Zeeman (gμB) 1T ~ 58 μeV

Tunneling coupling energy ( $hI$ ) 10 μeV ( $I = e\Gamma = 0.4$  nA)

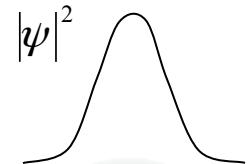
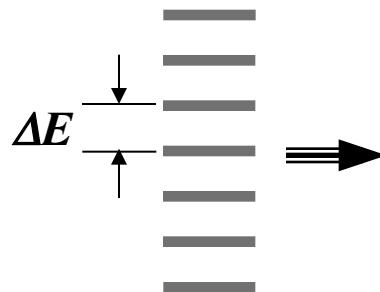
Josephson coupling energy  $\left( \frac{\Delta}{2} \frac{R_Q}{R_T} \right)$  10 μeV (for Al junctions,  $R_T = 64\text{k}\Omega$ )

Microwave energy ( $hf$ ) 1 GHz ≈ 4 μeV

# Quantum origin of energy level broadening



broadening of quantized levels



$\tau$  = time for electron to travel through the grain

in ballistic regime:  $\tau = L/v_F$

---

in diffusive regime:  $\tau = L^2/D$

Einstein relation:  $\sigma = e^2 D N_0(E_F) \Rightarrow \delta E \approx (\sigma h/e^2) [L^2 N_0(E_F)]^{-1}$   
Level spacing :  $\Delta E = [L^d N_0(E_F)]^{-1}$

Thouless ratio  $g \equiv \frac{\delta E}{\Delta E} \approx \frac{h}{e^2} \sigma L^{d-2} = \frac{G}{e^2/h}$

$g < 1$  ( $R > 26k\Omega$ )  $\Rightarrow$  localized state  
 $g > 1$  ( $R < 26k\Omega$ )  $\Rightarrow$  extended state